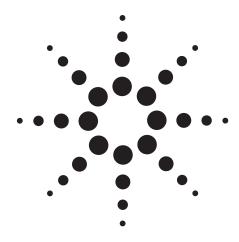
Digital Multimeter Measurement Errors Series

System Cabling Errors and DC Voltage Measurement Errors in Digital Multimeters

Application Note AN 1389-1



Introduction

When making measurements with a digital multimeter (DMM), common errors will crop up. The following discussion will help you eliminate potential measurement errors and achieve the greatest accuracy with a DMM. This paper covers system cabling errors and dc voltage measurement errors. For an overview of ac voltage measurement errors, see Application Note AN 1389-3. For a discussion of resistance; dc current; ac current; and frequency and period measurement errors, see Application Note AN 1389-2. (NOTE: The Agilent 34401A, a 6-1/2-digit, high-performance DMM with both benchtop and system features, will be used as an example throughout this article).

System Cabling Errors

Radio Frequency Interference -

Most voltage-measuring instruments can generate false readings in the presence of large, high-frequency signal sources such as nearby radio and television transmitters, computer monitors, and cellular telephones. Highfrequency energy can also be coupled to the multimeter on the system cabling. To reduce interference, try to minimize the exposure of the system cabling to high-frequency RF sources. If the application is extremely sensitive to RFI radiating from the multimeter, use a common mode choke in the system cabling, as shown in Figure 1, to attenuate multimeter emissions.

Thermal EMF Errors —

Thermoelectric voltages, the most common source of error in lowlevel voltage measurements, are generated when circuit connections are made with dissimilar metals at different temperatures. Each metal-to-metal junction forms a thermocouple, which generates a voltage proportional to the junction temperature. It is a good idea to take the necessary precautions to minimize thermocouple voltages and temperature variations in lowlevel voltage measurements. The best connections are formed using copper-to-copper crimped connections. Figure 2 shows common thermoelectric voltages for connections between dissimilar metals.

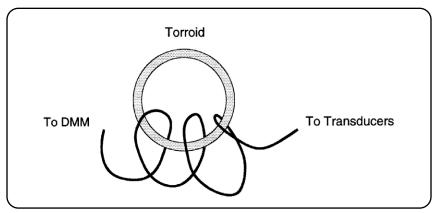


Figure 1.

When you make measurements near magnetic fields, take precautionary steps to avoid inducing voltages in the measurement connections. Voltage can be induced by either movement of the input connection wiring in a fixed magnetic field, or by a varying magnetic field. An unshielded, poorly dressed input wire moving in the earth's magnetic field can generate several millivolts. The varying magnetic field around the ac

power line can also induce

carrying large currents.

voltages up to several hundred

millivolts. Be especially careful

when working near conductors

Noise Caused by Magnetic Fields -

Copper-to-Approx. µV/°C Copper < 0.3 Gold 0.5 Silver 0.5 Brass 3 Beryllium Copper 5 Aluminum 5 Kovar or Alloy 42 40 500 Silicon Copper-Oxide 1000 Cadmium-Tin Solder 0.2 Tin-Lead Solder 5

Figure 2.

Where possible, route cabling away from magnetic fields, which are commonly present around electric motors, generators, televisions and computer monitors. In addition, when you are operating near magnetic fields, be certain that the input wiring has proper strain relief and is tied down securely. Use twisted-pair connections to the multimeter to reduce the noise pickup loop area, or dress the wires as closely together as possible.

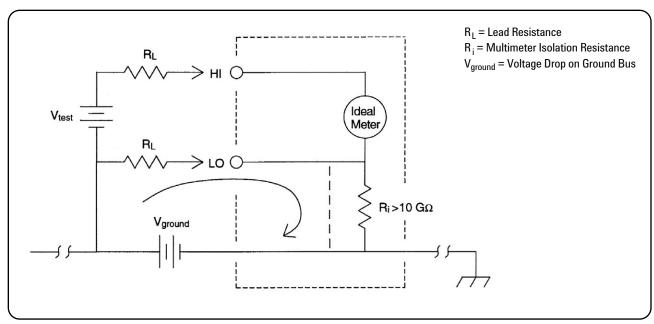


Figure 3.

Noise Caused by Ground Loops -

When you measure voltages in circuits where the multimeter and the device-under-test (DUT) are both referenced to a common earth ground, a $ground\ loop$ is formed. As shown in Figure 3, any voltage difference between the two ground reference points (V_{ground}) causes a current to flow through the measurement leads. This causes errors, such as noise and offset voltage (usually power-line related), which are added to the measured voltage.

The best way to eliminate ground loops is to maintain the multimeter's isolation from earth; do not connect the input terminals to ground. If the multimeter must be earth-referenced, be sure to connect it and the DUT to the same common ground point. This will reduce or eliminate any voltage difference between the devices. Also, whenever possible, make sure the multimeter and DUT are connected to the same electrical outlet.

DC Voltage Measurement Errors

Common Mode Rejection -

Ideally, a multimeter is completely isolated from earth-referenced circuits. However, there is finite resistance between the multimeter's input LO terminal and earth ground, as shown in Figure 4. This can cause errors when you measure low voltages that are floating relative to earth ground.

Noise Caused by Injected Current.

Residual capacitances in the multimeter's power transformer cause small currents to flow from the LO terminal to earth ground. The frequency of the *injected current* is the power line frequency or possibly harmonics of the power line frequency. The injected current is dependent upon the power line configuration and frequency. A simplified circuit is shown in Figure 5.

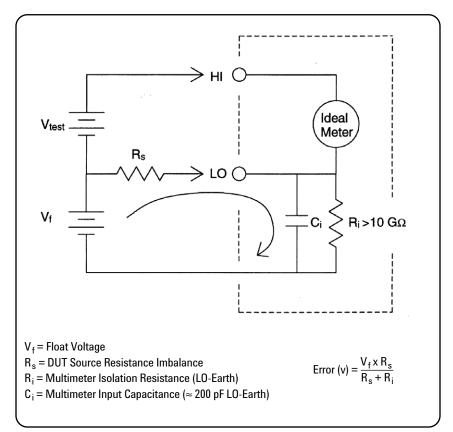


Figure 4.

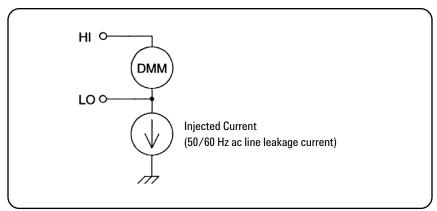


Figure 5.

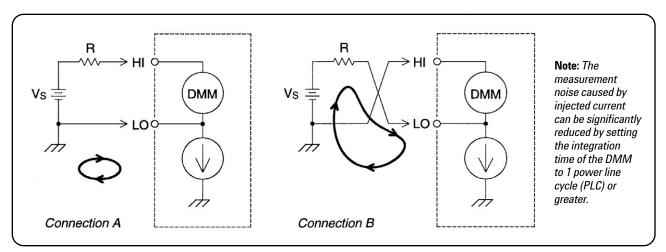


Figure 6.

With *Connection A* (see Figure 6), the injected current flows from the earth connection provided by the circuit to the LO terminal of the DMM, adding no noise to the measurement. However, with *Connection B*, the injected current flows through the resistor R, thereby adding noise to the measurement. With *Connection B*, larger values of R will worsen the problem.

Loading Errors Due to Input
Resistance — Measurement
loading errors occur when
the resistance of the DUT is an
appreciable percentage of the
multimeter's own input resistance.
Figure 7 shows this error source.

To reduce the effects of loading errors, and to minimize noise pickup, set the Agilent 34401A's input resistance to greater than 10 G Ω for the 100 mVdc, 1 Vdc, and 10 Vdc ranges. The input resistance is maintained at 10 M Ω for the 100 Vdc and 1000 Vdc ranges.

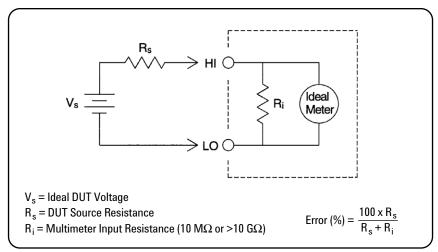


Figure 7.

Loading Errors Due to Input Bias Current – The multimeter's input capacitance will "charge up" due to input bias currents when the terminals are open-circuited (if the input resistance is $10 \text{ G}\Omega$). The multimeter's measuring circuitry exhibits approximately 30 pA of input bias current for ambient temperatures from 0 $^{\circ}\mathrm{C}$ to 30 °C. Bias current will double (x2) for every 8 °C change in ambient temperature above 30 °C. This current generates small voltage offsets dependent upon the source resistance of the DUT. This effect becomes evident for a source resistance of greater than $100 \text{ k}\Omega$, or when the multimeter's operating temperature is significantly greater than 30 °C.

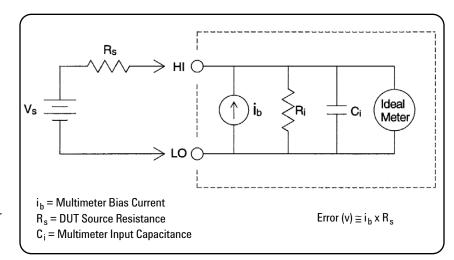


Figure 8.

Conclusion

A modern DMM such as the 34401A has many features to help protect you from many common sources of error. However, when making low-level or precise measurements, you must be more aware of sources that contribution to measurement errors. Environmental conditions - such as changes in temperature, RF signals and electromagnetic fields - will have a significant impact on the quality of DMM measurements. Once the measurement environment has been optimized, proper cabling can significantly reduce measurement errors. The remaining sources of error can be calculated and added to the measurement uncertainty.

For more information about the Agilent 34401A, go to www.agilent.com/find/34401a

Agilent Technologies' Test and Measurement Support, Services, and Assistance Agilent Technologies aims to maximize the value you receive, while minimizing your risk and problems. We strive to ensure that you get the test and measurement capabilities you paid for and obtain the support you need.

and measurement capabilities you paid for and obtain the support you need. Our extensive support resources and services can help you choose the right Agilent products for your applications and apply them successfully. Every instrument and system we sell has a global warranty. Support is available for at least five years beyond the production life of the product. Two concepts underlie Agilent's overall support policy: "Our Promise" and "Your Advantage."

Our Promise

Our Promise means your Agilent test and measurement equipment will meet its advertised performance and functionality. When you are choosing new equipment, we will help you with product information, including realistic performance specifications and practical recommendations from experienced test engineers. When you use Agilent equipment, we can verify that it works properly, help with product operation, and provide basic measurement assistance for the use of specified capabilities, at no extra cost upon request. Many self-help tools are available.

Your Advantage

Your Advantage means that Agilent offers a wide range of additional expert test and measurement services, which you can purchase according to your unique technical and business needs. Solve problems efficiently and gain a competitive edge by contracting with us for calibration, extra-cost upgrades, out-of-warranty repairs, and on-site education and training, as well as design, system integration, project management, and other professional engineering services. Experienced Agilent engineers and technicians worldwide can help you maximize your productivity, optimize the return on investment of your Agilent instruments and systems, and obtain dependable measurement accuracy for the life of those products.

By internet, phone, or fax, get assistance with all your test & measurement needs Online assistance: www.agilent.com/find/assist

Phone or Fax

United States:

(tel) 1 800 452 4844

Canada:

(tel) 1 877 894 4414 (fax) (905) 282 6495

China:

(tel) 800 810 0189 (fax) 800 820 2816

Europe:

(tel) (31 20) 547 2323 (fax) (31 20) 547 2390

Japan:

(tel) (81) 426 56 7832 (fax) (81) 426 56 7840

Korea:

(tel) (82 2) 2004 5004 (fax) (82 2) 2004 5115

Latin America:

(tel) (305) 269 7500 (fax) (305) 269 7599

Taiwan:

(tel) 080 004 7866 (fax) 080 028 6331

Other Asia Pacific Countries:

(tel) 1 800 375 8100 (fax) (65) 836 0252 (e-mail) tm_asia@agilent.com

Product specifications and descriptions in this document subject to change without notice.

© Agilent Technologies, Inc. 2002

Printed in the USA January 31, 2002

5988-5511EN

